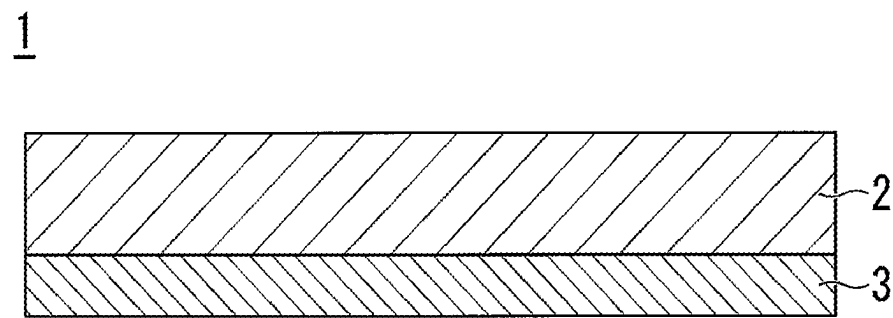


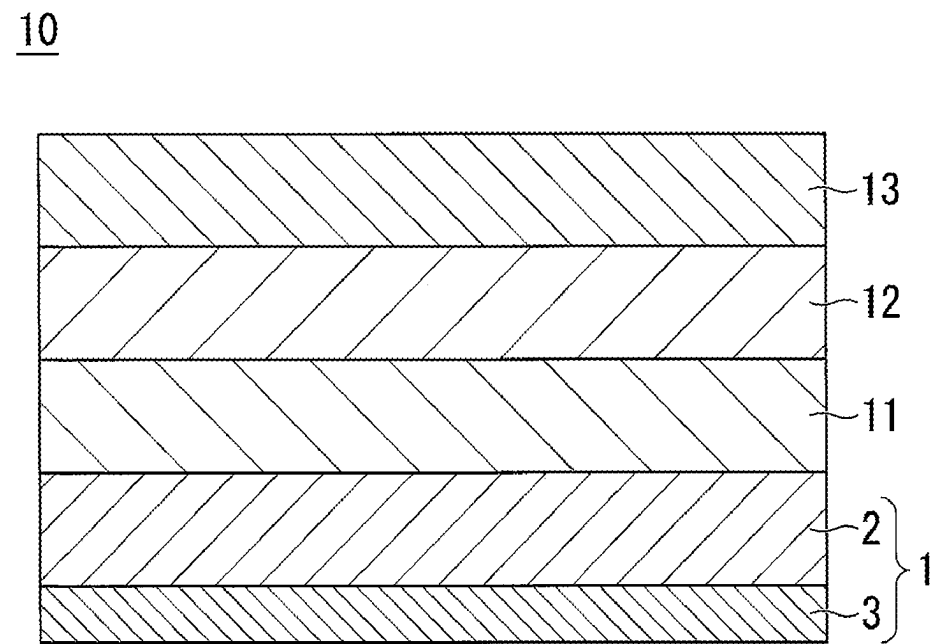




【FIG. 1】



【FIG. 2】















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In addition, the light emitting layer may further include at least one functional layer for controlling electrons and/or holes injected to the light emitting layer.

The encapsulation layer is for preventing oxygen and/or moisture from penetrating the light emitting layer. Materials forming the encapsulation layer are not particularly limited, and, the encapsulation layer may be formed as an inorganic layer or an organic layer, or formed in a multilayer structure in which an inorganic layer and an organic layer are alternately laminated. Examples of the inorganic layer material may include silicon nitride (SiNx), silicon oxide (SiOx), silicon oxynitride (SiON) or aluminum oxide (AlxOy), and examples of the organic layer material may include a benzocyclobutene resin, an epoxy resin, an acrylic resin, a polyamide resin, a polyimide resin or the like.

The organic EL display device of the present disclosure may have other functional layers installed in addition to the above-described layer structures. Examples of such other functional layers may include a touch panel layer, a hard coating layer, an adhesive layer, an antireflection layer, an antistatic layer and the like.

The organic EL display device of the present disclosure has high transparency. Preferably, the organic EL display device of the present disclosure may have total light transmittance of 70% or greater, preferably 80% or greater and more preferably 90% or greater in a visible region. The total light transmittance in a visible region may be measured using, for example, a visible light transmittance meter.

Such an organic EL display device of the present disclosure uses, as a support substrate, the support substrate for a display device of the present disclosure formed with a TFT glass substrate having a thickness of 10  $\mu$ m to 150  $\mu$ m, and a polyimide resin layer having a thickness of 150 nm or less and having high heat resistance installed in contact with the TFT glass substrate, and as a result, high transparency is obtained while being thin and having flexibility.

[Method for Manufacturing Organic EL Display Device]

The present disclosure also relates to a method for manufacturing an organic EL display device. The method for manufacturing an organic EL display device of the present disclosure includes a process of forming a polyimide resin layer having a thickness of 20 nm to 150 nm on a glass substrate, a process of installing a TFT glass substrate having a thickness of 10  $\mu$ m to 150  $\mu$ m on the polyimide resin layer, a process of forming a TFT circuitry layer on the TFT glass substrate, a process of installing a light emitting layer on the TFT circuitry layer, and a process of encapsulating the light emitting layer with an encapsulation layer, and also includes a process of peeling the polyimide resin layer from the glass substrate by irradiating laser light on the polyimide resin layer.

The process of forming a polyimide resin layer having a thickness of 20 nm to 150 nm on a glass substrate is a process of installing a polyimide resin layer having a thickness of 20 nm to 150 nm on a glass substrate that is a carrier substrate. The method for forming a polyimide resin layer is not particularly limited, however, the polyimide resin layer may be formed by coating a precursor NMP solution of the polyimide resin to a thickness of 100 nm to 750 nm, and then drying and curing the result. The drying condition is not particularly limited, but may be, for example, heating for 10 minutes to 10 hours at 50° C. to 300° C. In addition, the curing condition is not particularly limited, but may be, for example, heating for 10 minutes to 3 hours at a temperature of higher than 300° C. to 500° C. The method of coating a polyimide resin is not particularly limited, and methods known in the art may be used, and for example, a spin

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coating method, a slit coating method, a spray coating method, a roll coating method, a bar coating method and the like may be included as an example. Curing of a polyimide resin is normally conducted by heating. In addition, the thickness of the glass substrate that is a carrier substrate is not particularly limited, and, for example, may be from 0.1 mm to 30 mm.

The process of installing a TFT glass substrate having a thickness of 10  $\mu$ m to 150  $\mu$ m on the polyimide resin layer is a process of laminating a glass substrate for forming a TFT circuit on the polyimide resin layer obtained in the above-described process. The polyimide resin layer and the TFT glass substrate are normally adhered by heating. The heating condition is not particularly limited, but may be, for example, heating for 1 minute to 30 minutes at 300° C. to 400° C.

The process of forming a TFT circuitry layer on the TFT glass substrate is a process of forming a TFT circuit on the TFT glass substrate laminated in the above-described process. The process of forming a TFT circuit is conducted by forming a gate electrode, a gate insulating film, a semiconductor layer, a source electrode and a drain electrode using methods known in the art. In addition, although the TFT circuitry layer is not particularly limited, examples thereof may include a TFT circuitry layer formed with a thin film transistor having a semiconductor layer formed with amorphous silicon, polycrystalline silicon, low-temperature polysilicon or microcrystalline silicon. Such a process of forming a TFT circuitry layer commonly includes a process of annealing a semiconductor layer for 1 hour to 5 hours at 400° C. to 450° C.

The process of installing a light emitting layer including an organic layer on the TFT circuitry layer is a process of forming an organic EL light emitting layer on the TFT circuitry layer formed in the above-described process. The light emitting layer may be formed using methods known in the art, and may commonly include a hole injection layer, a hole transfer layer, an organic layer, an electron transfer layer and an electron injection layer consecutively laminated on a first electrode. Herein, a driving circuit of the TFT circuitry layer and the light emitting layer are electrically connected. Each of the layers may be formed using a deposition method, or may be formed using a coating method.

The process of encapsulating the light emitting layer with an encapsulation layer is a process of installing an encapsulation layer on the light emitting layer formed in the above-described process. Materials forming the encapsulation layer are not particularly limited, and, may be formed as an inorganic layer or an organic layer, or formed in a multilayer structure in which an inorganic layer and an organic layer are alternately laminated. Examples of the inorganic layer material may include silicon nitride (SiNx), silicon oxide (SiOx), silicon oxynitride (SiON) or aluminum oxide (AlxOy), and examples of the organic layer material may include a benzocyclobutene resin, an epoxy resin, an acrylic resin, a polyamide resin, a polyimide resin or the like. In addition, the encapsulation layer may be formed using methods known in the art, and for example, a sputter method, a vacuum deposition method, a plasma CVD method, an ion plating method and the like may be used.

The method for manufacturing an organic EL display device of the present disclosure also includes, in addition to the above-described processes, a process of peeling the polyimide resin layer from the glass substrate by irradiating laser light on the polyimide resin layer. In other words, the method for manufacturing an organic EL display device of

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the present disclosure includes a process of, in order to take out the organic EL display device, peeling the polyimide resin layer from the glass substrate by irradiating laser light on the polyimide resin layer and thereby changing an interface between the glass substrate that is a carrier substrate and the polyimide resin.

In the process of peeling the polyimide resin layer from the glass substrate, laser light is irradiated on the polyimide resin layer from a side of the glass substrate that is a carrier substrate. The wavelength of the laser light is not particularly limited as long as it is capable of changing the polyimide resin, but is normally ultraviolet. The laser light is preferably irradiated using a laser lift off method.

The changing of an interface between the glass substrate and the polyimide resin by irradiating laser light on the polyimide resin layer may include baking of the polyimide resin layer. Therefore, the thickness of the polyimide resin layer decreases by irradiating laser light, and the thickness of the polyimide resin layer after the peeling may be smaller than the thickness of the polyimide resin layer originally formed. In other words, the thickness of the polyimide resin layer of the organic EL display device after the peeling is 150 nm or less, preferably 100 nm or less, more preferably 90 nm or less and even more preferably 80 nm or less. A lower limit of the thickness of the polyimide resin layer is not particularly limited, however, the thickness is, for example, greater than 0.01 nm, 0.1 nm or greater, 1 nm or greater, 5 nm or greater, or 10 nm or greater. The thickness of the polyimide resin layer may be measured by observing, for example, the cross section using a transmission electron spectroscopy (TEM).

In existing technologies, there has been a problem in that, when a 10  $\mu$ m to 150  $\mu$ m thin layer glass substrate is used as a support substrate and this thin layer glass substrate is in direct contact with a glass substrate as a carrier substrate, peeling the thin layer glass substrate from the glass substrate becomes difficult when exposed to a high temperature during a process of forming a TFT circuit. The peeling process of the present disclosure is a case of installing a polyimide resin layer with high heat resistance between a glass substrate as a carrier substrate and a thin layer glass substrate, and using the thin layer glass substrate as a support substrate by changing the interface between the polyimide resin layer and the glass substrate using laser light, and the support substrate may be readily peeled from the glass substrate even when exposed to a high temperature. Accordingly, the present disclosure also relates to a use of a polyimide resin composition for peeling a 10  $\mu$ m to 150  $\mu$ m thin layer glass substrate from a glass substrate as a carrier substrate, and this polyimide resin composition forms a polyimide resin layer having a thickness of 150 nm or less.

According to the method for manufacturing an organic EL display device of the present disclosure, an organic EL display device including a support substrate for a display device formed with a TFT glass substrate having a thickness of 10  $\mu$ m to 150  $\mu$ m and a polyimide resin layer having a thickness of 150 nm or less installed in contact with the TFT glass substrate may be manufactured, and as a result, an organic EL display device having high transparency while being thin and having flexibility may be manufactured.

Hereinafter, the present disclosure will be described in detail with reference to the following example and comparative example. However, the present disclosure is not limited to the descriptions of the following example.

#### Example

A varnish including 4,4'-oxydiphthalic anhydride (ODPA) as an acid dianhydride and 2,2'-bis(trifluoromethyl)benzi-

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dine (TFMB) as a diamine was coated to a thickness of 500 nm on a glass substrate having a thickness of 0.5 mm using a slot die. The result was introduced to a nitrogen oven (manufactured by Koyo Thermo Systems Korea, Co., Ltd.), and dried for 30 minutes at 50° C., then dried for 30 minutes at 100° C., dried for 30 minutes at 150° C., dried for 30 minutes at 200° C., dried for 30 minutes at 250° C., dried for 30 minutes at 300° C., and cured for 30 minutes at 350° C. to form a polyimide resin layer having a thickness of 100 nm. Subsequently, thin layer glass (manufactured by Nippon Electric Glass Co., Ltd.) having a thickness of 50  $\mu$ m was laminated on the polyimide resin layer as a TFT glass substrate, and the result was heated for 10 minutes at 350° C. to adhere the polyimide resin layer and the thin layer glass as a TFT glass substrate. Subsequently, a TFT circuitry layer and a light emitting layer were formed on the thin layer glass using known methods, and an encapsulation layer was formed on the light emitting layer to form a display device on the glass substrate. In the process of forming a TFT circuitry layer, a semiconductor layer was annealed for 2 hours at 450° C. Lastly, the polyimide resin layer was peeled from the glass substrate by irradiating laser light with a wavelength of 308 nm on the polyimide resin layer from a surface opposite to the display device-laminated surface of the glass substrate using a laser lift off method, and as a result, an organic EL display device was obtained. The thickness of the polyimide resin layer of the obtained organic EL display device measured by observing a cross-section TEM was 70 nm.

#### Comparative Example

An organic EL display device was manufactured in the same manner as in Example except that thin layer glass was laminated on an epoxy resin layer using a general epoxy resin layer instead of the polyimide resin layer, and then the result was heated for 10 minutes at 160° C. In the process of forming a TFT circuitry layer, the epoxy resin layer foamed when annealing a semiconductor layer for 2 hours at 450° C., and an organic EL display device was not able to be manufactured since the epoxy resin layer and the thin layer glass were peeled off.

[Evaluation]

(Visible Light Transmission Test)

Transmittance of the organic EL display device obtained in Example for visible light was measured using a visible light transmittance meter (manufactured by Nippon Spectroscopy, UV-500). The organic EL display device of Example had total light transmittance of 90% or greater in a visible region. Therefore, the organic EL display device of the present disclosure had excellent transparency.

#### INDUSTRIAL APPLICABILITY

The support substrate for a display device of the present disclosure has high transparency, and, for example, is particularly useful for electronic devices equipped with a plurality of modules such as smart phones or tablets. For example, in electronic devices such as portable information terminals equipped with a camera module and a display device, it is possible to install the camera module on the back of the display device.

The invention claimed is:

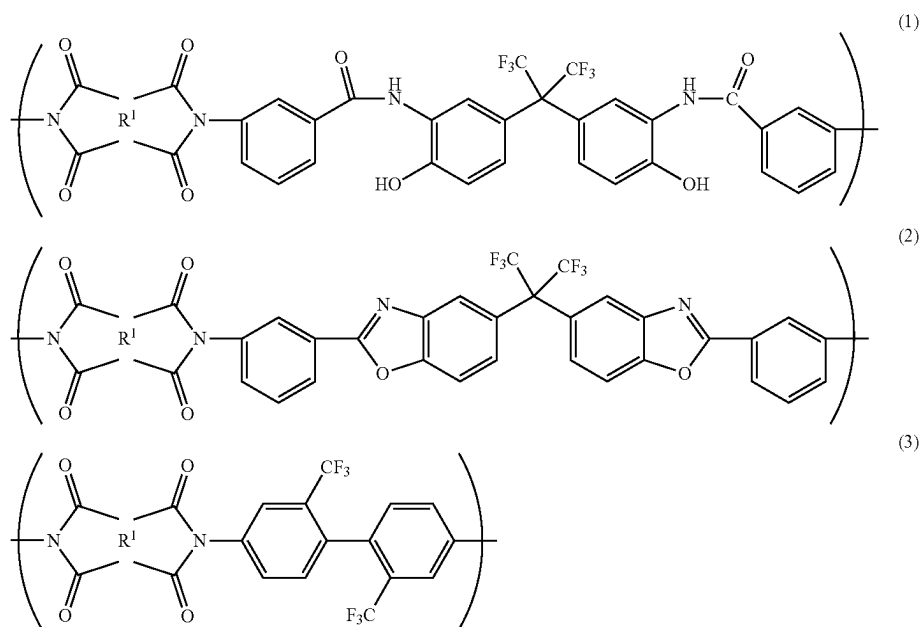
1. A support substrate for a display device comprising: a TFT glass substrate having a thickness of 10  $\mu$ m to 150  $\mu$ m;

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- a polyimide resin layer having a thickness of 150 nm or less installed in contact with the TFT glass substrate; and
- a TFT circuitry layer installed on the TFT glass substrate, wherein the TFT circuitry layer is installed in contact with the TFT glass substrate on a side of the TFT glass substrate that is opposite to the side of the TFT glass substrate in contact with the polyimide resin layer, wherein the polyimide resin layer comprises a polyimide resin formed from at least one acid dianhydride selected from 4,4'-oxydiphthalic anhydride (ODPA), 3,3',4,4'-biphenyltetracarboxylic dianhydride (BPDA), 2,2-bis(4-(3,4-dicarboxyphenoxy) phenyl) propane dianhydride (BSAA), 4,4'-(hexafluoroisopropylidene) diphthalic anhydride (6FDA) or 1,2,3,4-cyclobutanetetracarboxylic dianhydride (CBDA) and at least one diamine selected from 2,2-bis [3-(3-aminobenzamide)-4-hydroxyphenyl] hexafluoropropane (HFHA), trans-1,4-diaminocyclohexane or 2,2'-bis(trifluoromethyl) benzidine (TFMB), and
- wherein the support substrate has a total light transmittance of 70% or greater in a visible region after exposure to heat at 450° C. for 120 minutes.
2. The support substrate for a display device of claim 1, wherein the display device is an organic EL display device.
  3. The support substrate for a display device of claim 1, wherein the polyimide resin layer has a thickness of 0.1 nm or greater.

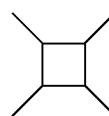
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- a process of forming a polyimide resin layer having a thickness of 20 nm to 150 nm on a glass substrate;
- a process of forming a TFT glass substrate having a thickness of 10 μm to 150 μm on the polyimide resin layer;
- a process of forming a TFT circuitry layer on the TFT glass substrate on a side of the TFT glass substrate that is opposite to the side of the TFT glass substrate in contact with the polyimide resin layer;
- a process of installing a light emitting layer including an organic layer on the TFT circuitry layer; and
- a process of encapsulating the light emitting layer with an encapsulation layer, and
- a process of peeling the polyimide resin layer from the glass substrate by irradiating laser light on the polyimide resin layer.
8. An organic EL display device comprising the support substrate for a display device of claim 2.
  9. An organic EL display device comprising the support substrate for a display device of claim 3.
  10. An organic EL display device comprising the support substrate for a display device of claim 4.
  11. An organic EL display device comprising the support substrate for a display device of claim 5.
  12. The support substrate for a display device of claim 1, wherein the polyimide resin comprises at least one of repeating structure units represented by Formulae (1) to (3):



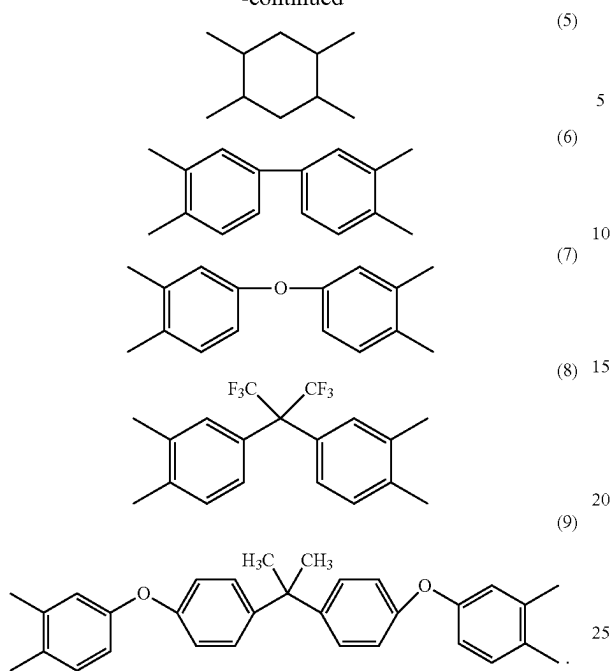
4. The support substrate for a display device of claim 1, wherein the polyimide resin layer has a thickness of 100 nm or less.
5. The support substrate for a display device of claim 1, wherein the TFT glass substrate has a thickness of 30 μm to 100 μm.
6. An organic EL display device comprising the support substrate for a display device of claim 1.
7. A method for manufacturing an organic EL display device, the method comprising:

wherein, in the Formulae (1) to (3), R<sup>1</sup> is at least one or more groups represented by (4) to (9):



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-continued



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